

## MOS FIELD EFFECT TRANSISTOR

 $\mu$ PA1763

# SWITCHING DUAL N-CHANNEL POWER MOS FET INDUSTRIAL USE

#### DESCRIPTION

The  $\mu$ PA1763 is N-Channel MOS Field Effect Transistor designed for DC/DC Converters.

#### **FEATURES**

- · Dual chip type
- · Low on-resistance
- ★ RDS(on)1 = 47.0 m $\Omega$  MAX. (Vgs = 10 V, ID = 2.3 A)
- ★ RDS(on)2 = 57.0 m $\Omega$  MAX. (Vgs = 4.5 V, ID = 2.3 A)
- ★ RDS(on)3 = 66.0 m $\Omega$  MAX. (Vgs = 4.0 V, ID = 2.3 A)
  - · Low input capacitance
- ★ Ciss = 870 pF TYP.
  - Built-in G-S protection diode
  - Small and surface mount package (Power SOP8)

# 8 5 1 : Source 1 2 7, 8 : Stafe 1 7, 8 : Stafe 2 7, 6 : Drain 2 8 : Stafe 2 7, 7 : Stafe 2 7,

PACKAGE DRAWING (Unit: mm)

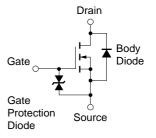
#### **ORDERING INFORMATION**

PART NUMBER	PACKAGE
μPA1763G	Power SOP8

#### ABSOLUTE MAXIMUM RATINGS (TA = 25 °C, All terminals are connected.)

	Drain to Source Voltage	VDSS	60	V	
	Gate to Source Voltage	Vgss	±20	V	
	Drain Current (DC)	I <sub>D(DC)</sub>	±4.5	Α	
	Drain Current (pulse) Note1	D(pulse)	±18	Α	
	Total Power Dissipation (1 unit) Note2	Рт	1.7	W	
	Total Power Dissipation (2 unit) Note2	Рт	2.0	W	
*	Single Avalanche Current Note3	las	4.5	Α	
*	Single Avalanche Energy Note3	Eas	60	mJ	
	Channel Temperature	Tch	150	°C	
	Storage Temperature	T <sub>stg</sub>	-55 to + 150	°C	

### EQUIVALENT CIRCUIT (1/2 Circuit)



- **Notes 1.** PW  $\leq$  10  $\mu$ s, Duty cycle  $\leq$  1 %
  - **2.** T<sub>A</sub> = 25 °C, Mounted on ceramic substrate of 1200 mm<sup>2</sup> x 2.2 mm
- 3. Starting T<sub>ch</sub> = 25 °C, R<sub>G</sub> = 25  $\Omega$ , V<sub>GS</sub> = 20 V  $\rightarrow$  0 V

**Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage Exceeding the rated voltage may be applied to this device.

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Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

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10%

VGS(on

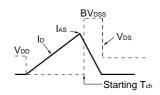


#### **★** ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25 °C, All terminals are connected.)

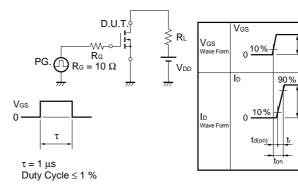
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, ID = 2.3 A		37.0	47.0	mΩ
	RDS(on)2	Vgs = 4.5 V, ID = 2.3 A		45.0	57.0	mΩ
	RDS(on)3	Vgs = 4.0 V, ID = 2.3 A		49.0	66.0	mΩ
Gate to Source Cut-off Voltage	V <sub>GS(off)</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	yfs	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 2.3 A	3.0	6.0		S
Drain Leakage Current	Ipss	Vps = 60 V, Vgs = 0 V			10	μΑ
Gate to Source Leakage Current	Igss	Vgs = ±16 V, Vps = 0 V			±10	μΑ
Input Capacitance	Ciss	Vps = 10 V		870		pF
Output Capacitance	Coss	Vgs = 0 V		150		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		80		pF
Turn-on Delay Time	td(on)	ID = 2.3 A		11		ns
Rise Time	tr	VGS(on) = 10 V		40		ns
Turn-off Delay Time	td(off)	VDD = 30 V		50		ns
Fall Time	tf	$R_G = 10 \Omega$		12		ns
Total Gate Charge	Q <sub>G</sub>	ID = 4.5 A		20		nC
Gate to Source Charge	Qgs	V <sub>DD</sub> = 48 V		3		nC
Gate to Drain Charge	Q <sub>GD</sub>	V <sub>G</sub> S = 10 V		5		nC
Body Diode Forward Voltage	V <sub>F</sub> (S-D)	IF = 4.5 A, VGS = 0 V		0.80		V
Reverse Recovery Time	trr	IF = 4.5 A, VGS = 0 V		30		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		40		nC

#### **TEST CIRCUIT 1 AVALANCHE CAPABILITY**

# $\begin{array}{c} \text{D.U.T.} \\ \text{Rg} = 25 \Omega \\ \text{VGS} = 20 \rightarrow 0 \text{V} \\ \end{array} \begin{array}{c} \text{PG.} \\ \text{Fig. 1} \\ \text{Fig. 2} \\ \text{Fig$



#### **TEST CIRCUIT 2 SWITCHING TIME**

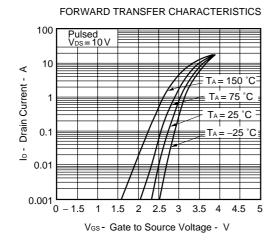


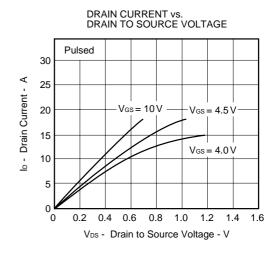
#### **★** TEST CIRCUIT 3 GATE CHARGE

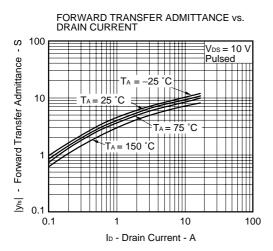
$$\begin{array}{c|c} \text{D.U.T.} \\ \text{Ig} = 2 \text{ mA} \\ \text{W} \\ \text{O} \end{array} \begin{array}{c} \text{I} \\ \text{F} \\ \text{F} \\ \text{M} \end{array} \begin{array}{c} \text{RL} \\ \text{VDD} \end{array}$$

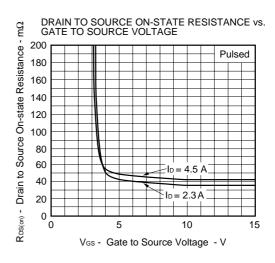


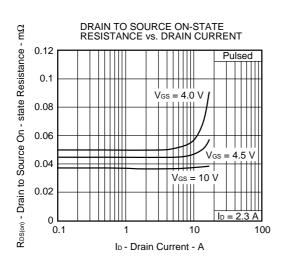
#### **★** TYPICAL CHARACTERISTICS (TA = 25°C, All terminals are connected.)

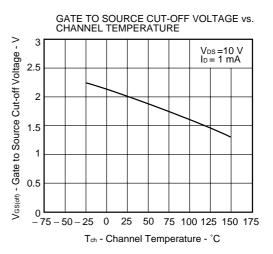


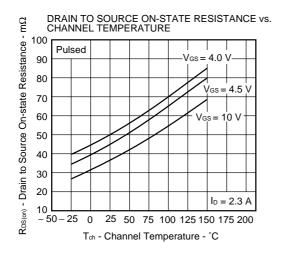


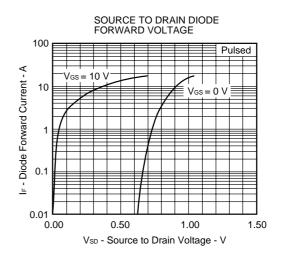


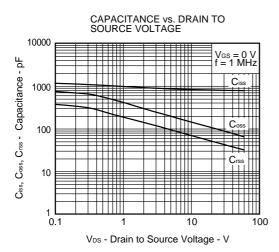


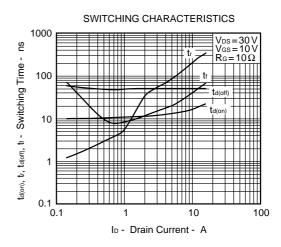


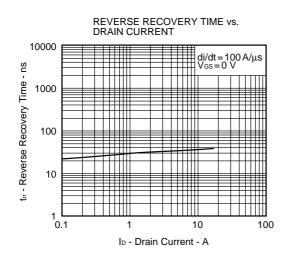


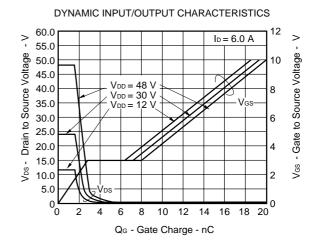


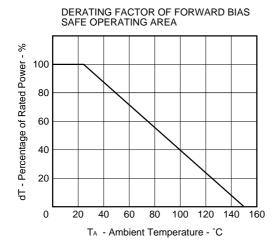


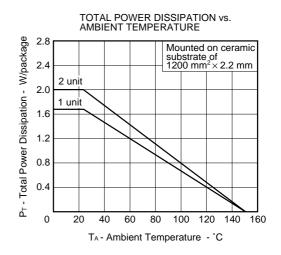


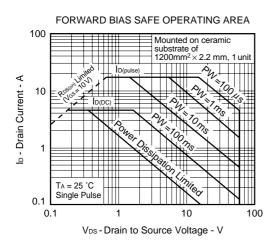




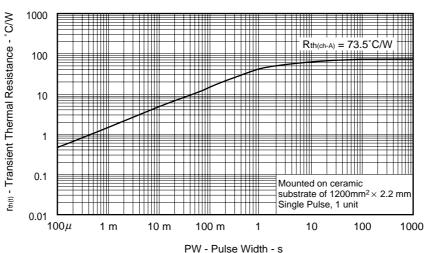






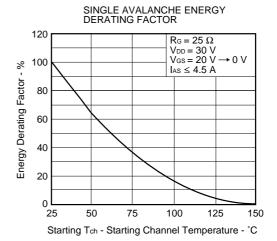


#### TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



#### 

L - Inductive Load - H



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[MEMO]

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